

# DIM200PKM33-F000

## **IGBT Chopper Module**

DS5465- 1.0 September 2005 (LN24183)

## **FEATURES**

- 10µs Short Circuit Withstand
- Soft Punch Through Silicon
- Isolated AISiC Base with AIN substrates
- High thermal cycling capability

## **APPLICATIONS**

- Choppers
- Motor Controllers
- Power Supplies
- Traction Auxiliaries

The Powerline range of high power modules includes half bridge, chopper, dual, single and bidirectional switch configurations covering voltages from 600V to 3300V and currents up to 2400A.

The DIM200PKM33-F000 is a 3300V, n channel enhancement mode, insulated gate bipolar transistor (IGBT) chopper module configured with the upper arm of the bridge controlled. The IGBT has a wide reverse bias safe operating area (RBSOA) plus full 10 $\mu$ s short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

## **ORDERING INFORMATION**

Order As:

#### DIM200PKM33-F000

Note: When ordering, please use the whole part number.

#### **KEY PARAMETERS**

V <sub>CES</sub>		3300V
V <sub>CE (sat)</sub> *	(typ)	2.8V
l <sub>c</sub>	(max)	200A
I <sub>C(PK)</sub>	(max)	400A

(measured at the power busbars and not the auxiliary terminals)

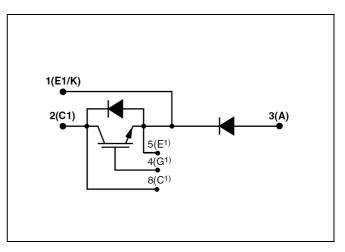


Fig. 1 Chopper circuit diagram

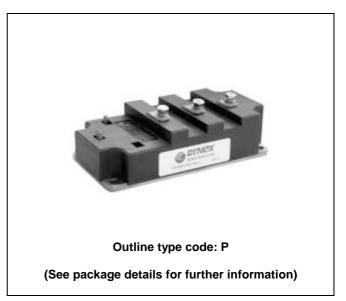




Fig. 2 Electrical connections (not to scale)



#### ABSOLUTE MAXIMUM RATINGS - PER ARM

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

#### Tcase = 25℃ unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	$V_{GE} = 0V$	3300	V
V <sub>GES</sub>	Gate-emitter voltage		±20	V
Ι <sub>C</sub>	Continuous collector current	T <sub>case</sub> = 90°C	200	А
I <sub>C(PK)</sub>	Peak collector current	1ms, T <sub>case</sub> =115℃	400	А
P <sub>max</sub>	Max. transistor power dissipation	T <sub>case</sub> = 25℃, T <sub>j</sub> = 150℃	2.6	W
l <sup>2</sup> t	Diode l <sup>2</sup> t value (IGBT arm) Diode l <sup>2</sup> t value (Diode arm)	$V_R = 0, t_P = 10ms, T_{vj} = 125$ °C	20 20	kA <sup>2</sup> S
Visol	Isolation voltage – per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	6000	V
Q <sub>PD</sub>	Partial discharge - per module	IEC1287. V <sub>1</sub> = 3500V, V <sub>2</sub> = 2600V, 50Hz RMS	10	рС



## THERMAL AND MECHANICAL RATINGS

Internal insulation material:	AIN
Baseplate material:	AISiC
Creepage distance:	33mm
Clearance:	20mm
CTI (Critical Tracking Index):	175

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance - transistor	Continuous dissipation – junction to case	-	-	48	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode (IGBT arm) Thermal resistance- diode ( Diode	Continuous dissipation –	-	-	96	℃/kW
	arm)	junction to case			96	℃/kW
$R_{th(c-h)}$	Thermal resistance – case to heatsink (per module)	Mounting torque 5Nm (with mounting grease)	-	-	16	°C/kW
Tj	Junction temperature	Transistor	-	-	150	C
		Diode	-	-	125	C
T <sub>stg</sub>	Storage temperature range	-	-40	-	125	C
-	Screw torque	Mounting – M6	-	-	5	Nm
		Electrical connections – M5	-	-	4	Nm



## **ELECTRICAL CHARACTERISTICS**

#### $T_{case} = 25^{\circ}C$ unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
I <sub>ces</sub>	Collector cut-off current	$V_{GE}$ = 0V, $V_{CE}$ = $V_{CES}$	-	-	1	mA
		$V_{GE}$ = 0V, $V_{CE}$ = $V_{CES}$ , $T_{case}$ = 125°C	-	-	15	mA
I <sub>ces</sub>	Gate leakage current	$V_{GE} = \pm 20V, V_{CE} = 0V$	-	-	1	μA
V <sub>GE(TH)</sub>	Gate threshold voltage	$I_C = 40 \text{mA}, V_{GE} = V_{CE}$	5.5	6.5	7.0	V
$V_{\text{CE(sat)}^\dagger}$	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 200A	-	2.8	-	V
		$V_{GE}$ = 15V, I <sub>C</sub> = 200A, T <sub>case</sub> = 125°C	-	3.6	-	V
I <sub>F</sub>	Diode forward current	DC	-	-	200	Α
I <sub>FM</sub>	Diode maximum forward current	t <sub>p</sub> = 1ms	-	-	400	A
V <sub>F</sub> †	Diode forward voltage (IGBT arm) Diode forward voltage (Diode arm)	I <sub>F</sub> = 200A	-	2.9 2.9	-	V
	Diode forward voltage (IGBT arm) Diode forward voltage (Diode arm)	I <sub>F</sub> = 200A, T <sub>case</sub> = 125℃	-	3.0 3.0	-	V
Cies	Input capacitance	$V_{CE} = 25V$ , $V_{GE} = 0V$ , $f = 1MHz$	-	36	-	nF
L <sub>M</sub>	Module inductance – per arm	-	-	40	-	nH
R <sub>INT</sub>	Internal resistance – per arm	-	-	0.5	-	mΩ
SC <sub>Data</sub>	Short circuit. I <sub>sc</sub>	$T_j = 125^{\circ}C, V_{cc} = 2500V,$ I	1 -	1000	-	Α
		$\label{eq:logical_states} \begin{array}{l} t_p \leq 10 \mu s, \\ V_{CE(max)} = V_{CES} \text{ - } L^* \textbf{x} di/dt \\ \\ IEC \ 60747\text{-}9 \end{array} \end{array} \qquad $	2 -	930	-	A

#### Note:

t Measured at the power busbars and not the auxiliary terminals

L is the circuit inductance + L<sub>M</sub>



#### **ELECTRICAL CHARACTERISTICS**

SEMICONDUCTOR

## $T_{case} = 25^{\circ}C$ unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 200A	-	1950	-	ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$	-	170	-	ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 1800V	-	220	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = R_{G(OFF)} = 16.5\Omega$	-	1180	-	ns
t <sub>r</sub>	Rise time	L ~ 100nH	-	225	-	ns
Qg	Gate charge	$C_{ge} = 56 nF$	-	5	-	μC
Eon	Turn-on energy loss	$R_{G(ON)} = 7.5\Omega$	-	290	-	mJ
Q <sub>rr</sub>	Diode reverse recovery charge	$I_F = 200A, V_R = 1800V,$	-	80	-	μC
Irr	Diode reverse current	dI <sub>F</sub> /dt = 1600A/µs	-	144	-	А
E <sub>REC</sub>	Diode reverse recovery energy	Diode arm	-	75	-	mJ

## $T_{case} = 125^{\circ}C$ unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 200A	-	2200	-	ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$	-	190	-	ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 1800V	-	265	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = R_{G(OFF)} = 16.5\Omega$	-	1150	-	ns
tr	Rise time	L ~ 100nH, C <sub>ge</sub> = 56nF	-	280	-	ns
E <sub>ON</sub>	Turn-on energy loss	$R_{G(ON)} = 7.5\Omega$	-	390	-	mJ
Qrr	Diode reverse recovery charge	I <sub>F</sub> = 200A, V <sub>R</sub> = 1800V,	-	125	-	μC
l <sub>rr</sub>	Diode reverse current	dI <sub>F</sub> /dt = 1600A/µs	-	155	-	А
E <sub>REC</sub>	Diode reverse recovery energy	Diode arm	-	130	-	mJ

SEMICONDUCTOR

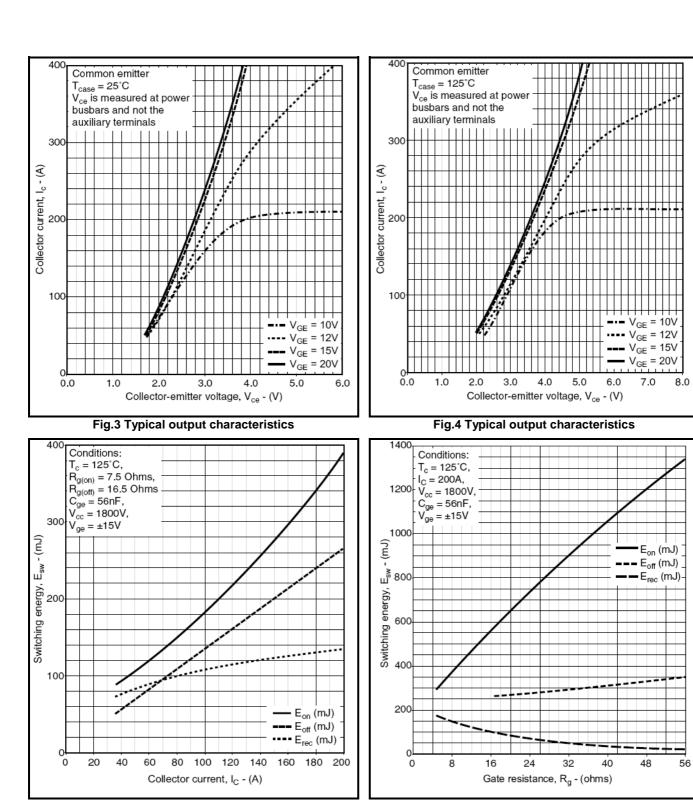


Fig.5 Typical switching energy vs collector current

Fig.6 Typical switching energy vs gate resistance

**C BYNEX** SEMICONDUCTOR

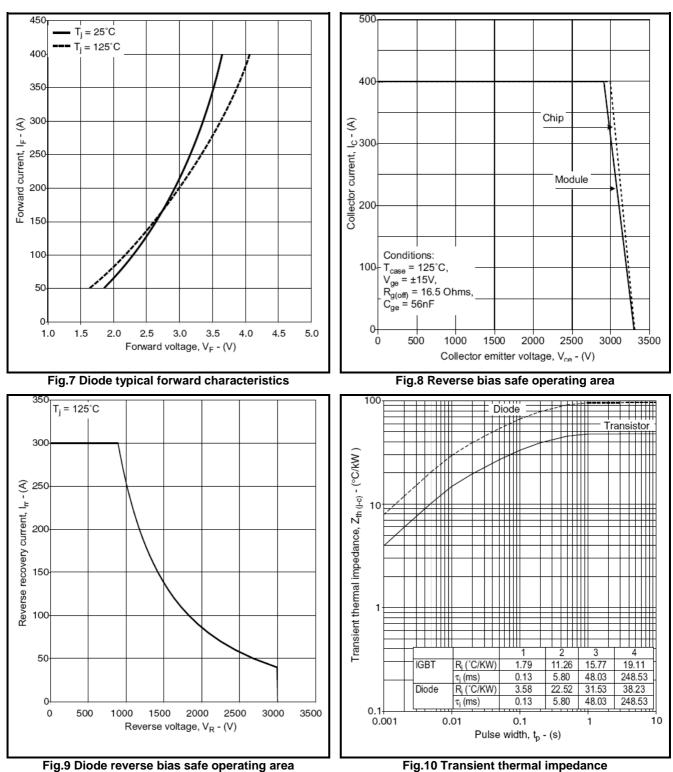
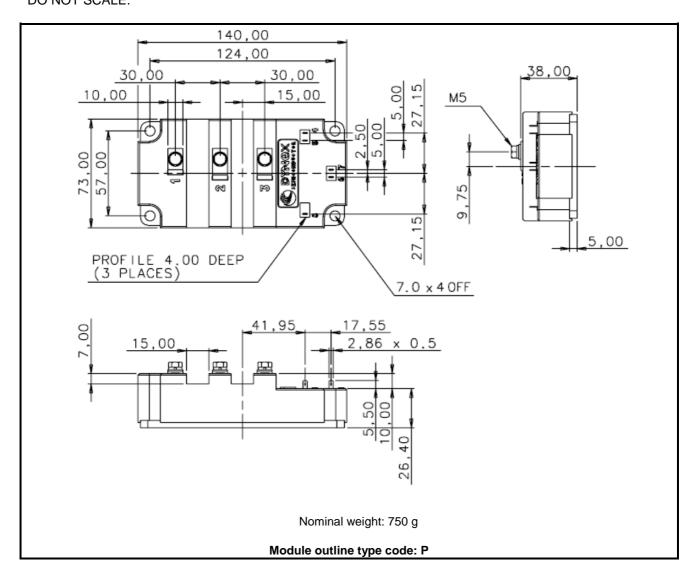


Fig.10 Transient thermal impedance



## PACKAGE DETAILS

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.





#### POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

#### HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.



http://www.dynexsemi.com

e-mail: power\_solutions@dynexsemi.com

HEADQUARTERS OPERATIONS **DYNEX SEMICONDUCTOR LTD** Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom. Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 CUSTOMER SERVICE Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

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